



**IEEE Los Alamos/Northern  
New Mexico Section**

**Northern New Mexico Section  
of ASME**



You are invited to a dinner meeting featuring noted expert on network and computer security

**Prof. Hal Berghel**

Associate Dean, Howard R. Hughes College of Engineering  
University of Nevada, Las Vegas

**Identity Theft and Financial Fraud for the New  
Millennium**

Dr. Berghel will discuss the latest computing and law enforcement perspectives on identity theft and financial fraud (ITFF). Topics will include credit/debit card scams and related technologies like keystroke logging, skimming, and double-scanning; fungible credentials, counterfeiting, digital forgery and credential amplification; advantages and disadvantages of anti-counterfeiting technologies; tactics for hiding data; what disk wiping doesn't do (well), etc. Actual illustrations of ITFF taken from law enforcement case files will be presented.

Dr. Berghel is currently Associate Dean of the Howard R. Hughes College of Engineering at the University of Nevada, Las Vegas and Director of both the Center for Cybermedia Research and Identity Theft and Financial Fraud Research and Operations Center. His current research focuses on computing and network security and forensics, digital white collar crime, and technologies to anticipate network security events-of-interest. He is a Fellow of both the IEEE Computer Society and Association for Computing Machinery and has received the ACM Outstanding Lecturer of the Year Award four times and was recognized for Lifetime Achievement in 2004. He is also the founder and owner of Berghel.net, a full-service information, computing and IT security consultancy.



Location: UNM-Los Alamos Student Center, Los Alamos, NM.  
Date: Tuesday, March 18<sup>th</sup>,  
Social time: 5:30pm, Dinner Buffet: 6-7pm, Speaker 7-8pm  
Cost: \$10 for IEEE and ASME members and guests, \$15 for non-members

RSVP by **March 11<sup>th</sup>** to David Izraelevitz, 667-3594 (w), 661-8878(h) or  
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